

Refine Search

Search Results -

Terms	Documents
semiconductor and (nanoscale same roughness).clms.	0

Database:

US Pre-Grant Publication Full-Text Database
 US Patents Full-Text Database
 US OCR Full-Text Database
 EPO Abstracts Database
 JPO Abstracts Database
 Derwent World Patents Index
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Search:

Refine Search

Recall Text
Clear
Interrupt

Search History

DATE: Monday, October 03, 2005 [Printable Copy](#) [Create Case](#)

<u>Set Name</u> <u>Query</u>	<u>Hit Count</u>	<u>Set Name</u> result set
side by side		
<i>DB=PGPB; PLUR=YES; OP=ADJ</i>		
<u>L7</u> semiconductor and (nanoscale same roughness).clms.	0	<u>L7</u>
<i>DB=JPAB; PLUR=YES; OP=ADJ</i>		
<u>L6</u> semiconductor and (nanoscale same roughness)	0	<u>L6</u>
<i>DB=EPAB; PLUR=YES; OP=ADJ</i>		
<u>L5</u> semiconductor and (nanoscale same roughness)	0	<u>L5</u>
<i>DB=USPT; PLUR=YES; OP=ADJ</i>		
<u>L4</u> semiconductor and (nanoscale same roughness)	27	<u>L4</u>
<i>DB=PGPB; PLUR=YES; OP=ADJ</i>		
<u>L3</u> semiconductor and (nanoscale same roughness)	40	<u>L3</u>
<i>DB=TDBD; PLUR=YES; OP=ADJ</i>		
<u>L2</u> semiconductor and (nanoscale same roughness)	1	<u>L2</u>
<i>DB=DWPI; PLUR=YES; OP=ADJ</i>		
<u>L1</u> semiconductor and (nanoscale same roughness)	1	<u>L1</u>

END OF SEARCH HISTORY